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1 **A fault coverage-driven partial scan chain selection technique**
Gloster, C., Jr.; Subramanian, S.;
ASIC Conference and Exhibit, 1994. Proceedings., Seventh Annual IEEE International , 19-23 Sept. 1994
Pages:366 - 369

[Abstract]   [PDF Full-Text (264 KB)]   **IEEE CNF**

---

2 **A novel scan architecture for power-efficient, rapid test [sequential circuits]**
Sinanoglu, O.; Orailoglu, A.;
Computer Aided Design, 2002. ICCAD 2002. IEEE/ACM International Conference on , 10-14 Nov. 2002
Pages:299 - 303

[Abstract]   [PDF Full-Text (450 KB)]   **IEEE CNF**

---

3 **Static test compaction for full-scan circuits based on combinational test sets and non-scan sequential test sequences**
Pomeranz, I.; Reddy, S.M.;
VLSI Design, 2003. Proceedings. 16th International Conference on , 4-8 Jan. 2003
Pages:335 - 340

[Abstract]   [PDF Full-Text (247 KB)]   **IEEE CNF**

---

4 **Reducing test power during test using programmable scan chain disable**
Sankaralingam, R.; Touba, N.A.;
Electronic Design, Test and Applications, 2002. Proceedings. The First IEEE International Workshop on , 29-31 Jan. 2002
Pages:159 - 163

[Abstract]   [PDF Full-Text (266 KB)]   **IEEE CNF**

---

5 **Reducing power dissipation during test using scan chain disable**
Sankaralingam, R.; Pouya, B.; Touba, N.A.;
VLSI Test Symposium, 19th IEEE Proceedings on. VTS 2001 , 29 April-3 May 2001
Pages:319 - 324

6 Hybrid BIST using partially rotational scan
Ichino, K.; Asakawa, T.; Fukumoto, S.; Iwasaki, K.; Kajihara, S.;
Test Symposium, 2001. Proceedings. 10th Asian , 19-21 Nov. 2001
Pages:379 - 384

[Abstract]   [PDF Full-Text (539 KB)]   IEEE CNF

7 Improving the test quality for scan-based BIST using a general test application scheme
Huan-Chih Tsai; Kwang-Ting Cheng; Bhawmik, S.;
Design Automation Conference, 1999. Proceedings. 36th , 21-25 June 1999
Pages:748 - 753

[Abstract]   [PDF Full-Text (552 KB)]   IEEE CNF

8 Full scan fault coverage with partial scan
Xijiang Lin; Pomeranz, I.; Reddy, S.M.;
Design, Automation and Test in Europe Conference and Exhibition 1999.
Proceedings , 9-12 March 1999
Pages:468 - 472

[Abstract]   [PDF Full-Text (180 KB)]   IEEE CNF

9 A partial scan methodology for testing self-timed circuits
Khoche, A.; Brunvand, E.;
VLSI Test Symposium, 1995. Proceedings., 13th IEEE , 30 April-3 May 1995
Pages:283 - 289

[Abstract]   [PDF Full-Text (612 KB)]   IEEE CNF

10 Hypertasking: automatic array and loop partitioning on the iPSC
Baber, M.;
System Sciences, 1991. Proceedings of the Twenty-Fourth Annual Hawaii
International Conference on , Volume: ii , 8-11 Jan. 1991
Pages:438 - 447 vol.2

[Abstract]   [PDF Full-Text (732 KB)]   IEEE CNF

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